

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 00862.022499		APPLICATION NO. Not Yet Assigned	
				APPLICANT Takao Yonehara, et al.			
				FILING DATE Currently herewith		GROUP Not Yet Assigned	

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
TN	5,206,749	4/27/93	Zavracky et al.	359	59	<div style="border-left: 1px solid black; border-right: 1px solid black; height: 100px; width: 100%;"></div>	
	5,256,562	10/26/93	Vu et al.	437	86		
	5,811,348	9/22/98	Matsushita, et al.	438	455		
	6,107,213	8/22/00	Tayanaka, et al.	438	762		
	5,985,742	11/16/99	Henley, et al.	438	515		
TN	5,856,229	1/5/99	Sakaguchi, et al.	438	406		

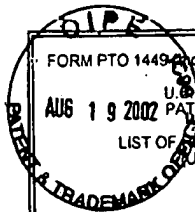
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
TN	9-312349	12/2/97	Japan	<div style="border-left: 1px solid black; border-right: 1px solid black; height: 100px; width: 100%;"></div>	<div style="border-left: 1px solid black; border-right: 1px solid black; height: 100px; width: 100%;"></div>	Abstract	
TN	886 300	12/23/98	EP			<div style="border-left: 1px solid black; border-right: 1px solid black; height: 100px; width: 100%;"></div>	

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		

EXAMINER <i>[Signature]</i>	DATE CONSIDERED 3/4/04
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

AUG 19 2002

LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

ATTY DOCKET NO.

00862.022499

APPLICATION NO.

10/059,171

APPLICANT

TAKAO YONEHARA, et al.

FILING DATE

January 31, 2002

GROUP

2871

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TW		6,190,937	02/20/2001	Nauagawa, et al.	438	67	
		6,222,513	03/10/1998	Howard, et al.	345	84	
		6,258,698	07/10/2001	Iwasaki, et al.	438	455	
		6,306,729	10/23/2001	Sauaguchi, et al.	438	458	
		6,331,208	12/18/2001	Nishida, et al.	117	89	
		6,342,433	01/29/2002	Ohmi, et al.	438	455	
TW		6,382,292	05/07/2002	Ohmi, et al.	156	584	

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
TW	EP	1 122 794	08/08/2001	Europe			
	EP	858 110	08/12/1998	Europe			
	EP	849 788	06/24/1998	Europe			
TW	JP	11-316397	11/16/1999	Japan	G02F		Abstract

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

TW		Shimoda, T., et al: "Surface Free Technology By Laser Annealing (SUFTLA)" International Electron Devices Meeting 1999. IEDM. Technical Digest. Washington, DC, Dec. 5-8, 1999, New York, NY: IEEE, US, Aug. 1, 1999 (1999-08-01), pages 289-292, XP000933199 ISBN: 0-7803-5411-7.

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DATE CONSIDERED

3/4/04

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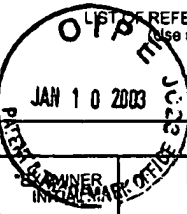
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FORM PTO 1448 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO. 00862.022499.

APPLICATION NO. 10/059,171

LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)APPLICANT **TAKAO YONEHARA, et al.**FILING DATE **January 31, 2002**GROUP **2871**

U.S. PATENT DOCUMENTS

OWNER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>TW</i>	6,075,280	06/13/00	Yung et al.	257	620	
<i> </i>	6,136,668	10/24/00	Tamaki, et al.	438	462	
	6,186,384	02/13/01	Sawada	225	2	
	6,465,329	10/15/02	Glenn	438	462	
	2002/0076904	06/20/02	Imler	438	462	
<i>TW</i>	2002/0100941	08/01/02	Yonehara, et al.	257	359	

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

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